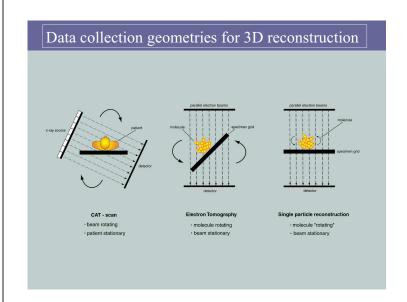
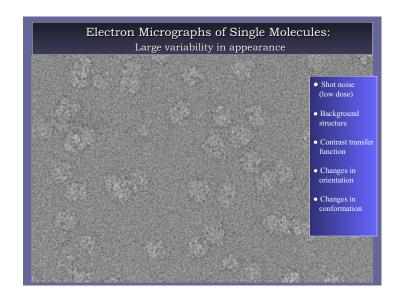
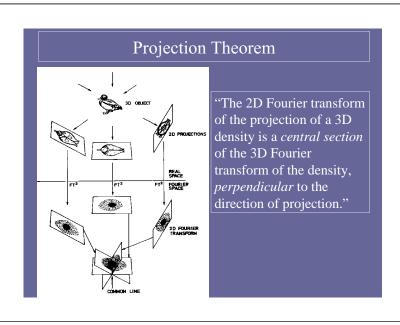
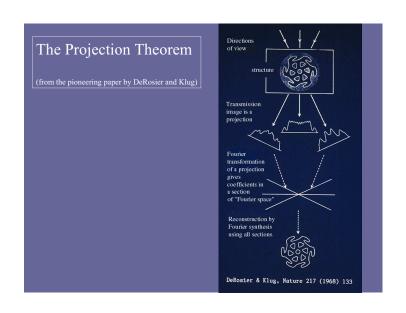


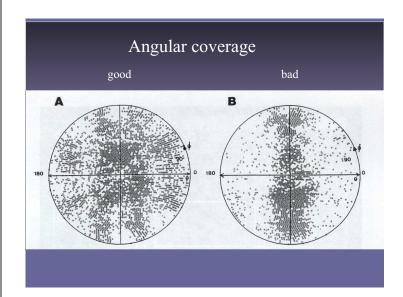
Single-particle reconstruction Main initial assumptions: 1) All particles in the specimen have identical structure 2) All are linked by 3D rigid body transformations (rotations, translations) 3) Particle images are interpreted as a "signal" part (= the projection of the common structure) plus "noise" Important requirement: even angular coverage, without major gaps.











Overview: the necessary steps of a singleparticle reconstruction

- 1) Optical diffraction: quality control, defocus inventory of micrograph batch
- 2) Scanning of batch of micrographs
- 3) Determine defoci, and define defocus groups
- 4) Pick particles
- 5) Determine particle orientation
- 6) 3D reconstruction by defocus groups
- 7) Refinement
- 8) CTF correction
- 9) Validation
- 10) Interpretation: segmentation, docking, etc.

Overview: tools

- 2D alignment
 - usually by cross-correlation (translational, rotational)
 - (a) reference-based
 - (b) reference-free
- Classification
 - (a) supervised (multi-reference, 3D projection matching)

 - - (a) phase residual(b) Fourier shell correlation
- (c) Spectral signal-to-noise ratio (SSNR)
 Low-pass filtration
 Amplitude correction (filter tailored acc. to experimental data)

Definition of the cross-correlation function (CCF)

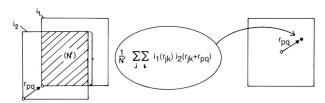


Fig. 3.8. Definition of the cross-correlation function. Image 1 is shifted with respect to image 2 by vector \mathbf{r}_{pq} . In this shifted position, the scalar product of the two images arrays is formed and put into the CCF matrix at position (p,q). The vector \mathbf{r}_{pq} is now allowed to assume all positions on the sampling grid. In the end, the CCF matrix has an entry in each position. From Frank (1980). Reproduced with permission of Springer-Verlag, New York.

Alignment methods designed to minimize the influence of the reference

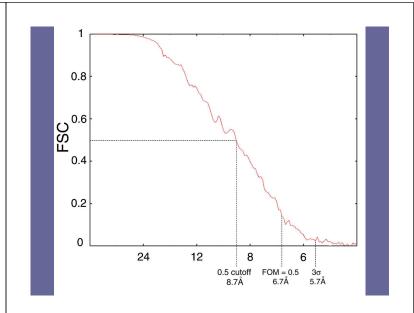
"Reference free" iterative alignment (Penczek et al., 1992): Two images are randomly picked, aligned, and added.
Then, a third image is aligned and added to the previous two. The process is repeated until all images are aligned.

the first image is realigned to [total average - image 1]. Then the second image is realigned to [total average - image 2], etc ...

The whole process is started again until no improvement is found between on alignment cycle and the next.

Resolution measures & criteria: Fourier shell correlation

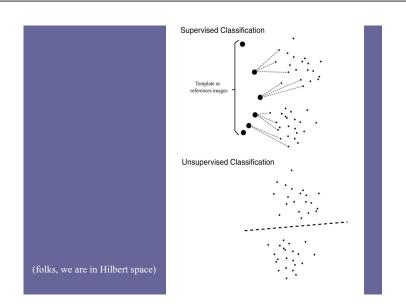
$$FSC(k, \Delta k) = \frac{Re \left| \sum_{[k, \Delta k]} F_1(\mathbf{k}) F_2^*(\mathbf{k}) \right|}{\left[\sum_{[k, \Delta k]} |F_1(\mathbf{k})|^2 |F_2(\mathbf{k})|^2 \right]^{1/2}}$$



Classification

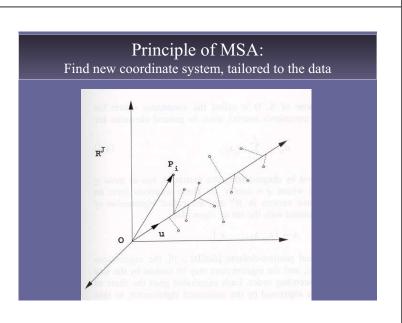
Classification methods are divided into those that are "supervised" and those that are "unsupervised":

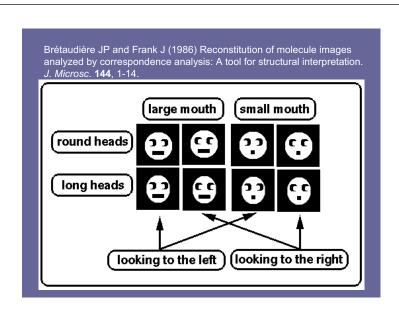
- Supervised: divide or categorize according to similarity with "template" or "reference".
 - Example for application: projection matching
- Unsupervised: divide according to intrinsic properties
 Example for application: find classes of projections presenting the same view

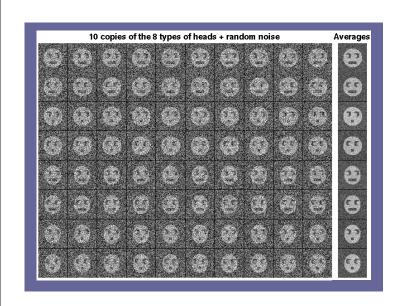


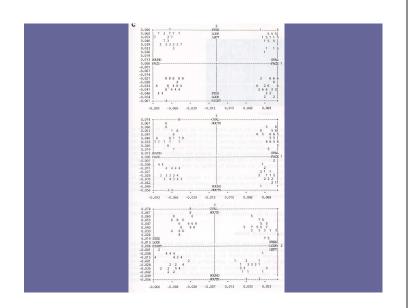
Classification, and the Role of MSA

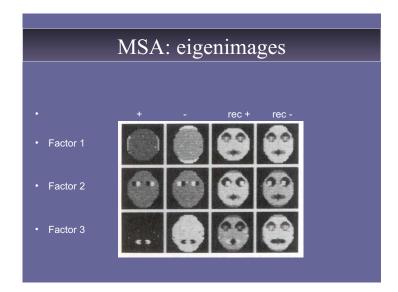
- Classification deals with "objects" in the space in which they are represented.
- For instance, a 64x64 image is an "object" in a 4096-dimensional space since, in principle, each of its pixels can vary independently.
 Let's say we have 8000 such images. They would form a cloud with 8000 points in this space.
- Unsupervised classification is a method that is designed to find clusters (regions of cohesiveness) in such a point cloud
- Role of Multivariate Statistical Analysis (MSA): find a space ("factor space") with reduced dimensionality for the representation of the "objects". This greatly simplifies classification
- Reasons for the fact that the space of representation can be *much smaller* than the
 original space: resolution limitation (neighborhoods behave the same), and
 correlations due to the physical origin of the variations (e.g., movement of a
 structural component is represented by correlated additions and subtractions at the
 leading and trailing boundaries of the component).

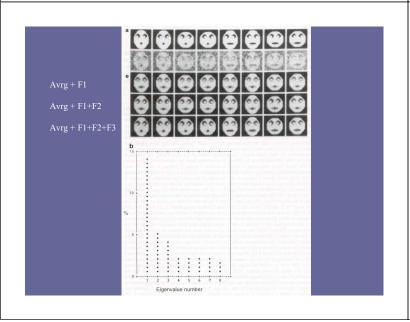




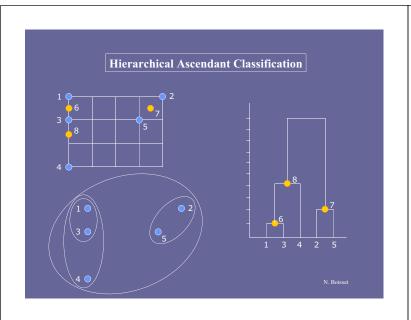


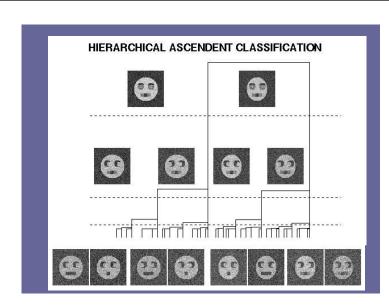


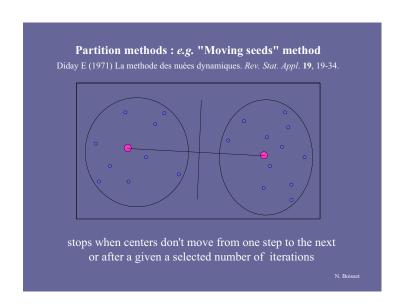


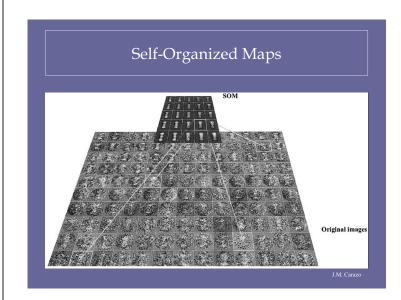


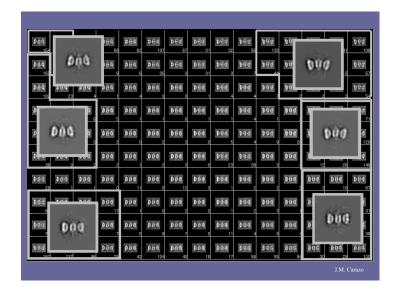
Hierarchical ascendant classification (HAC): find links between objects, and group these hierarchically, in ascendant order. Partitional methods: divide objects into a given number of clusters. Example: K-means. Self-organized maps (SOMs): create a 2D similarity order among objects, by a process of "negotiation", usually by means of a neural network.











particle reconstruction Optical diffraction: quality control, defocus inventory of micrograph batch Scanning of batch of micrographs

Overview: the necessary steps of a single-

- 3) Determine defoci, and define defocus groups
- 4) Pick particles
- 5) Determine particle orientation
- 6) 3D reconstruction by defocus groups
- 7) Angular refinement
- 8) CTF correction
- 9) Validation/determine resolution
- 10) Interpretation: segmentation, docking, etc.

Overview: the necessary steps of a singleparticle reconstruction -- I 2) Scanning of micrograph batch [I will skip both]3) Determine defoci, and define defocus groups (a) manual

(b) automated 5) Determine particle orientation (a) unknown structure -- bootstrap (i) random-conical (uses unsupervised classification) (ii) common lines/ angular reconstitution (uses unsupervised classification)

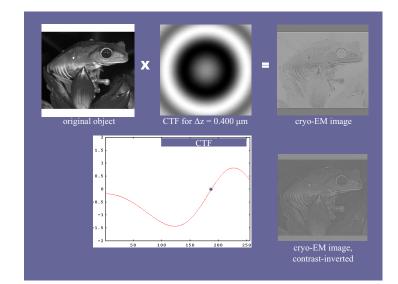
- (b) known structure
 (i) reference-based (3D projection matching = supervised classification)
- (ii) common lines/ angular reconstitution

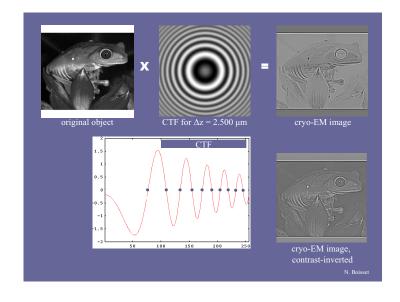
Overview: the necessary steps of a singleparticle reconstruction -- I

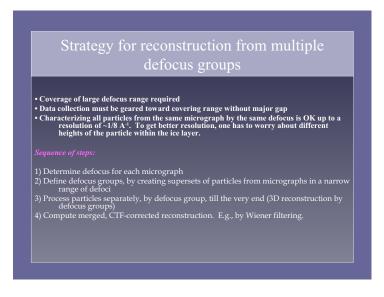
- 1) Optical diffraction: quality control, defocus inventory of micrograph batch
- 2) Scanning of micrograph batch
- - (a) manual
- 5) Determine particle orientation

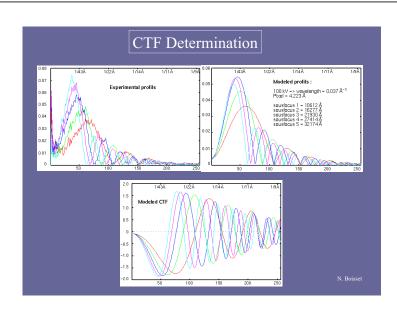
 - (a) unknown structure -- bootstrap (i) random-conical (uses unsupervised classification)
 - (ii) common lines/ angular reconstitution (uses unsupervised classification)

 - (b) known structure (i) reference-based (3D projection matching = supervised classification)





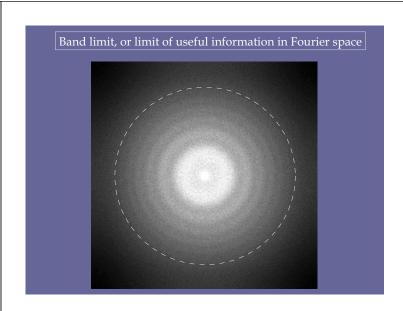


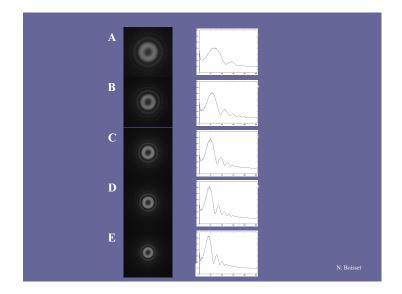


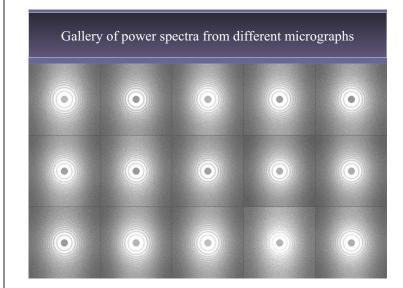
Computation of averaged power spectrum

For each micrograph ...

- 1) Divide field into overlapping subfields of \sim 512 x 512
- 2) Compute FFT for each subfield
- 3) Compute $|F(k)|^2$ for each subfield
- 4) Form average over $|F(k)|^2$ of all subfields => averaged, smoothed power spectrum
- 5) Take square root of result => "power spectrum" with reduced dynamic range
- 6) Form azimuthal average => 1D profile, characteristic for the micrograph, ready to be compared with CTF







Overview: the necessary steps of a singleparticle reconstruction -- I

- 1) Optical diffraction: quality control, defocus inventory of micrograph batch
- 2) Scanning of micrograph batch3) Determine defoci, and define defocus groups

- 5) Determine particle orientation
 (a) unknown structure -- bootstrap

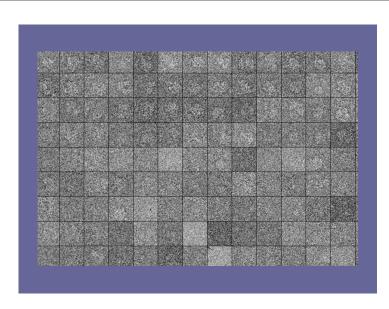
 - (a) unknown structure bootstrap

 (i) random-conical (uses unsupervised classification)

 (ii) common lines/ angular reconstitution (uses unsupervised classification)

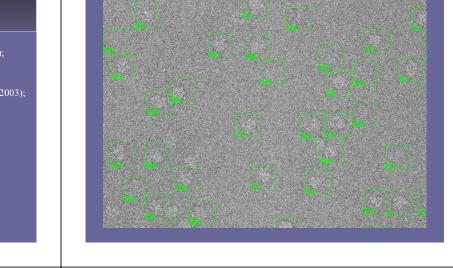
 (b) known structure

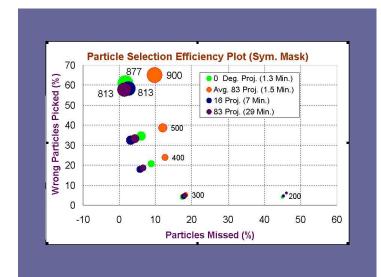
 - (i) reference-based (3D projection matching = supervised classification)

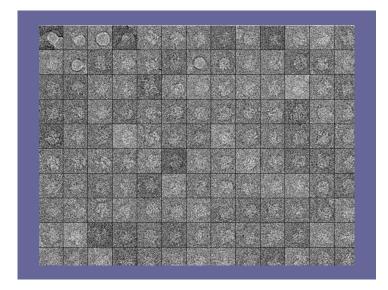


Automated particle picking, CCF-based, with local normalization

- (i) Define a reference (e.g., by averaging projections over full Eulerian range);
- (ii) Paste reference into array with size matching the size of the micrograph;
- (iii) Compute CCF via FFT;
- (iv) Compute locally varying variance of the micrograph via FFT (Roseman, 2003);
- "Local CCF" = CCF/local variance
- (vi) Peak search;
- (vii) Window particles ranked by peak size;







Overview: the necessary steps of a singleparticle reconstruction -- I

- 1) Optical diffraction: quality control, defocus inventory of micrograph batch
- 2) Scanning of micrograph batch
- 3) Determine defoci, and define defocus groups
- 4) Pick particles
- ermine particle orientation

 (a) unknown structure -- bootstrap

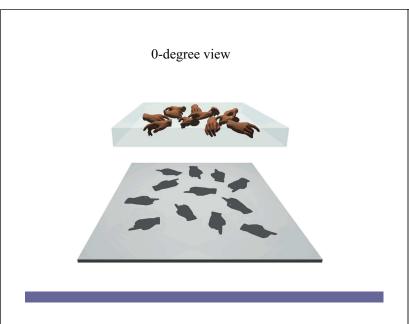
 (i) random-conical (uses unsupervised classification)

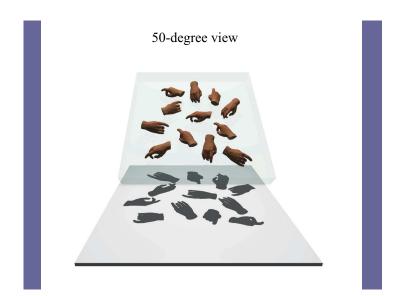
 (ii) common lines/ angular reconstitution (uses unsupervised classification)

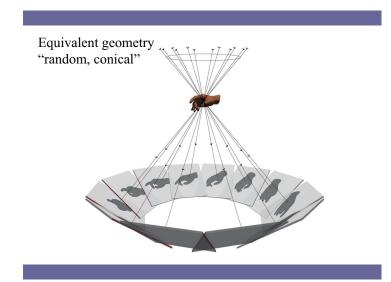
 (b) known structure
 - - (i) reference-based (3D projection matching = supervised classification)
 - (ii) common lines/ angular reconstitution

Random-conical reconstruction

- Premise: all particles exhibit the same view (could be a subset, determined by classification)
- Take same field first at theta ~50 degrees, then at 0 degrees (in this order, to minimize dose)
- Display both fields side by side
- Align particles from 0-degree field
- Assign azimuths and theta to the tilted particles

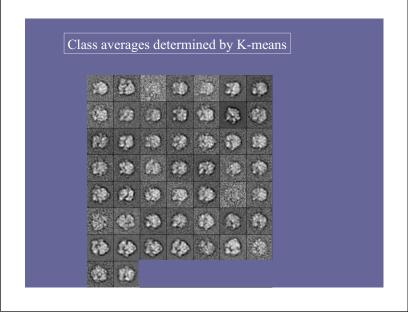


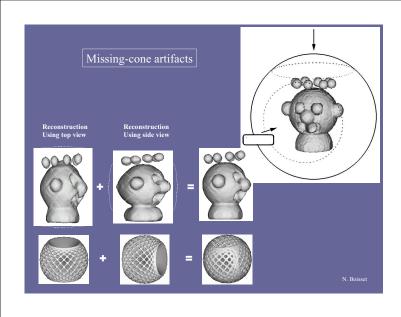




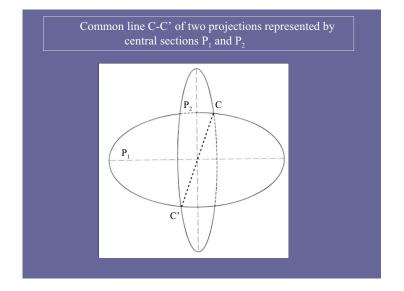
Random-conical reconstruction -- Problems to be solved:

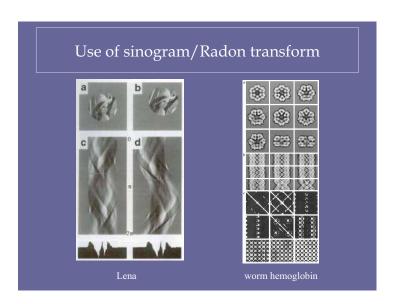
- 1) Find a subset (view class) of particles that lie in the same orientation on the grid answer: unsupervised classification of 0-degree particles
- 2) Missing-cone problem answer: do several random conical reconstructions, each from a different subset (view class), find relative orientations, then make reconstruction from merged projections set.

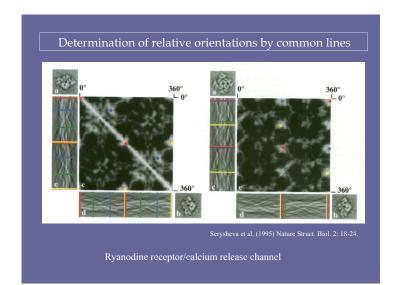




Overview: the necessary steps of a singleparticle reconstruction -- I 1) Optical diffraction: quality control, defocus inventory of micrograph batch 2) Scanning of micrograph batch 3) Determine defoci, and define defocus groups 4) Pick particles (a) manual (b) automated 5) Determine particle orientation (a) unknown structure -- bootstrap (i) random-conical (uses unsupervised classification) (ii) common lines/ angular reconstitution (uses unsupervised classification) (b) known structure (i) reference-based (3D projection matching = supervised classification) (ii) common lines/ angular reconstitution

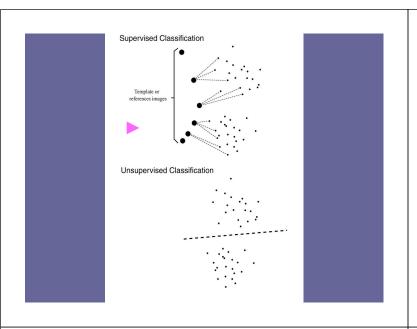


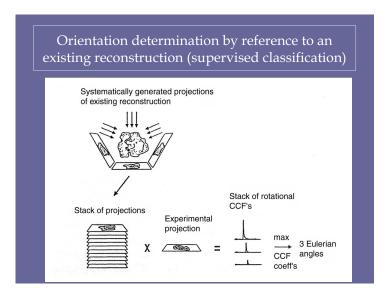




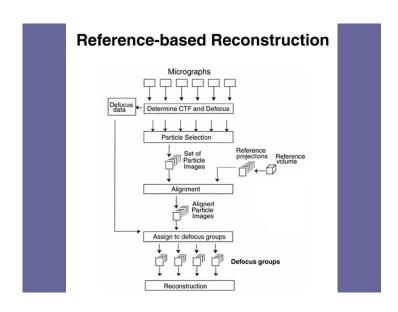
Common lines/angular reconstitution 1) Unsupervised classification, to determine classes of particles exhibiting the same view 2) Average images in each class → class averages 3) Determine common lines between class averages stepwise (van Heel, 1987) -- or -- simultaneously (Penczek et al., 1996) Issues: • unaveraged images are too noisy - class averages must be used • resolution loss due to implicit use of view range • handedness not defined - tilt or prior knowledge needed

Overview: the necessary steps of a single-particle reconstruction -- I 1) Optical diffraction: quality control, defocus inventory of micrograph batch 2) Scanning of micrograph batch 3) Determine defoci, and define defocus groups 4) Pick particles (a) manual (b) automated 5) Determine particle orientation (a) unknown structure -- bootstrap (i) random-conical (uses unsupervised classification) (ii) common lines/ angular reconstitution (uses unsupervised classification) (b) known structure (i) reference-based (3D projection matching = supervised classification) (ii) common lines/ angular reconstitution



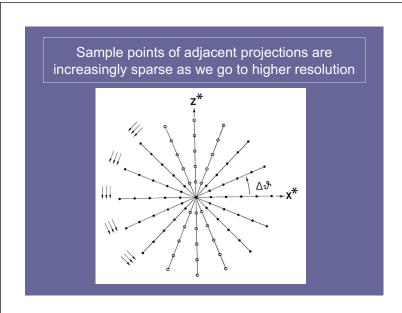


Initial Angular Grid 83 directions ~15 degrees separation



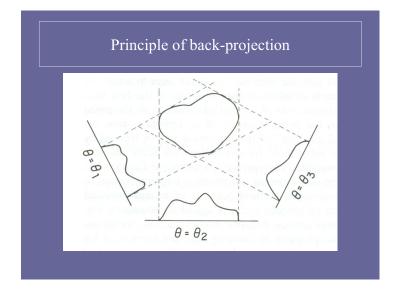
Overview: the necessary steps of a singleparticle reconstruction -- II 6) 3D reconstruction by defocus group (a) Fourier interpolation (b) Weighted back-projection (c) Iterative algebraic reconstruction (d) Conjugate gradient 7) Refinement • given an initial 3D reference, iterate the steps {3D projection matching + reconstruction} • beware of problem of reference-dependence 11) CTF correction 12) Validation 10) Interpretation: segmentation, docking, etc.

(a) Fourier interpolation (b) Weighted back-projection (c) Iterative algebraic reconstruction (d) Conjugate gradient 1) Obtain samples on a regular Cartesian grid in 3D Fourier space by interpolation between Fourier values on oblique 2D grids (central sections) running through the origin, each grid corresponding to a projection. 2) Speed (high) versus accuracy (low). 3) Can be used in the beginning phases of a reconstruction project.



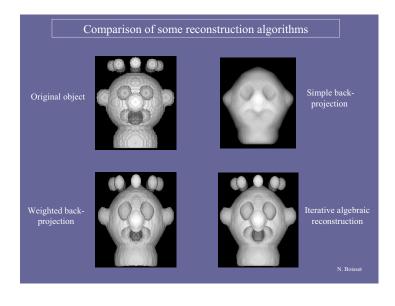
3D reconstruction by defocus group

- (a) Fourier interpolation
- (b) Weighted back-projection
- (c) Iterative algebraic reconstruction
- (d) Conjugate gradient
- (1) Simple back-projection: Sum over "back-projection bodies", each obtained by "smearing out" a projection in the viewing direction.
- (2) Weighted back-projection: as (1), but "weight" the projections first by multiplying their Fourier transforms with |K| (R* weighting, in X-ray terminology), then inversing the Fourier transform.
- (3) For general geometries, the weighting function is more complicated, and has to be computed every time.
- Weighted back-projection is fast, but does not yield the "smoothest" results. It may show strong artifacts related to angular gaps.



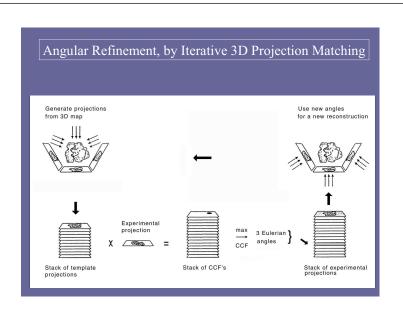
3D reconstruction by defocus group

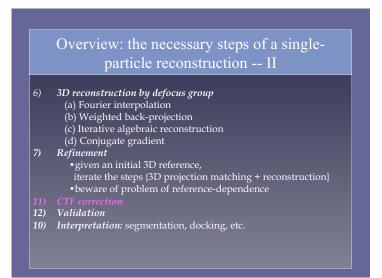
- (a) Fourier interpolation
- (b) Weighted back-projection
- (c) Iterative algebraic reconstruction
- (d) Conjugate gradient
- 1) The discrete algebraic projection equation is satisfied, one angle at a time, by adjusting the densities of a starting volume. As iterations proceed, each round produces a better approximation of the object.
- 2) The algorithm comes in many variants. It allows constraints to be easily implemented
- 3) It produces a very smooth reconstruction, and is less affected by angular gaps

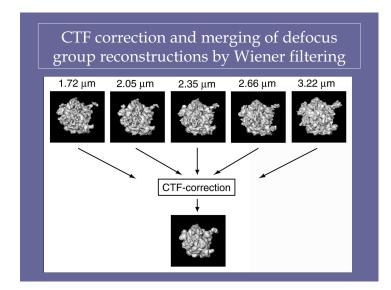


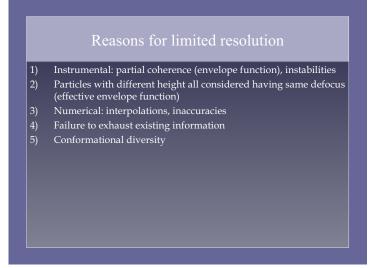
Overview: the necessary steps of a singleparticle reconstruction -- II

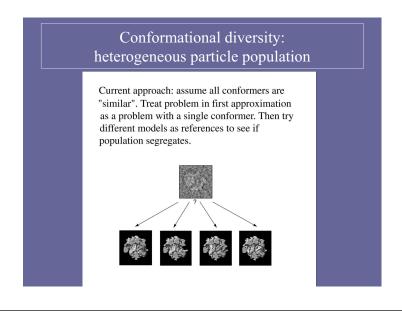
- 6) 3D reconstruction by defocus group
 - (a) Fourier interpolation
 - (b) Weighted back-projection
 - (c) Iterative algebraic reconstruction
 - (d) Conjugate gradient
-) Refinement
 - given an initial 3D reference,
 - beware of problem of reference-dependence
- 11) CTF correction
- 12) Validation
- 10) *Interpretation:* segmentation, docking, etc.

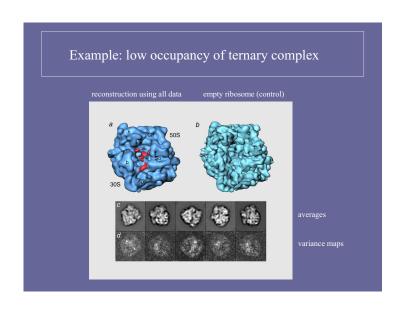


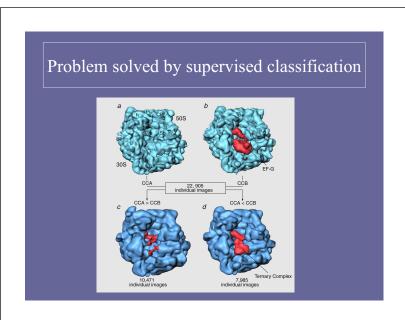












Conclusions:

Many tools & strategies available now Mix and match!

Software should accommodate mix & match, by providing interfaces and complying to certain standards and conventions. Atomic resolution is just around the corner (but the corner for some reason moves farther and farther away)